IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Harald Boehm, et al.   Docket No.: DE920000077US1

Serial No.: 09/960,154   Group Art Unit: 2113

Filed: September 21, 2001   Examiner: Scott T. Baderman

For: Method and System for Testing a Processor

Mail Stop Amendment
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT
TRANSMITTAL LETTER

Sir:

Please find enclosed a listing (PTO Form 1449) of references which may be

relevant to the above-referenced application. This listing of references is not a

representation that a search has been made, that better references than listed do not

exist, or that other references are not applicable. Moreover, this listing does not

constitute any admission by applicants or applicants' attorney that the information

provided herein is necessarily prior art to applicants' invention. **Please charge any fee**

necessary to enter this paper to deposit account 09-0468.

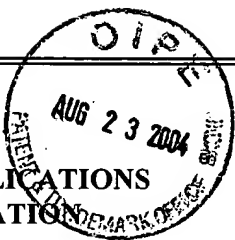Dated: <u>August 20, 2004</u>   Respectfully submitted,

Rafael Perez-Pineiro
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IBM Corporation
Intellectual Property Law Dept.
P.O. Box 218
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FORM PTO-1449 (Modified)	ATTY. DOCKET NO.	SERIAL NO.:
	DE920000077US1	09/960,154
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	**APPLICANT:** Harald Boehm, et al.	
	FILING DATE: 09/21/2001	**GROUP: 2113**

REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS**

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
	AA						
	AB						RECEIVED
	AC						AUG 2 7 2004
	AD						Technology Center 2100
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	AG	WO 97/13209	04/10/1997	WIPO			Yes	
	AH							
	AI							
	AJ							
	AK							
	AL							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AM	"An Integrated CAD System for Algorithm-Specific IC Design," C. S. Shung, R. Jain, K. Rimey, E. Wang, M. Srivastava, E. Lettang, S. K. Azim, P. N. Hilfinger, J. Rabaey, R. W. Brodersen, 1989 IEEE, pgs. 82-91.

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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